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ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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Title of Invention

ETCHING OPENINGS OF DIFFERENT DEPTHS USING A
SINGLE MASK LAYER METHOD AND STRUCTURE

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David Dobuzinsky

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or 6348374 or 6124216 or 6008540 or 6339002 or 5422309 or 6110648 or 6265303
or 6221780 or 6255211 or 6566276 or 6406963 or 6361837 or 6211035 or 6351039
or 6472312 or 6025276).pn

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
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Signature

Examiner Name	Date
<i>William H. H. H.</i>	12/16/04